BEILSTEIN JOURNAL OF NANOTECHNOLOGY

Supporting Information

for

Revealing local structural properties of an atomically thin $MoSe_2$ surface using optical microscopy

Lin Pan, Peng Miao, Anke Horneber, Alfred J. Meixner, Pierre-Michel Adam and Dai Zhang

Beilstein J. Nanotechnol. **2022,** *13,* 572–581. doi:10.3762/bjnano.13.49

Additional experimental data

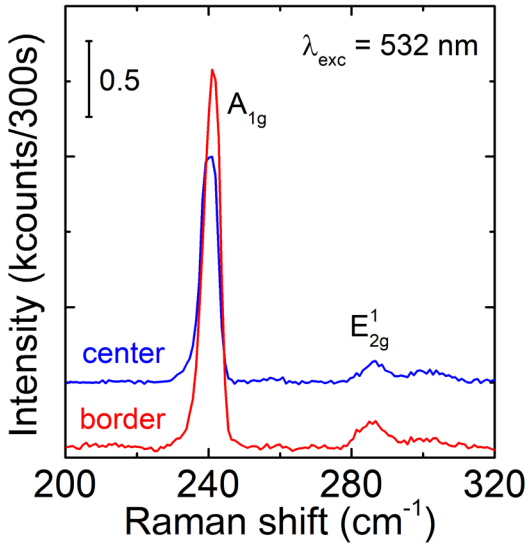

Figure S1: Raman spectra obtained from the border and center regions of a $MoSe_2$ flake with a 532 nm laser as the excitation source.

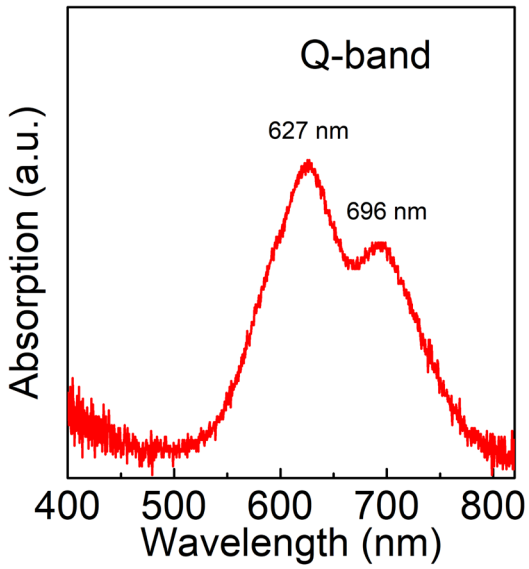

Figure S2: Absorption spectrum of a CuPc film with a thickness of 10 nm on a glass substrate. Two absorption peaks are located at 627 and 696 nm, which belong to the Q-band absorption of CuPc.

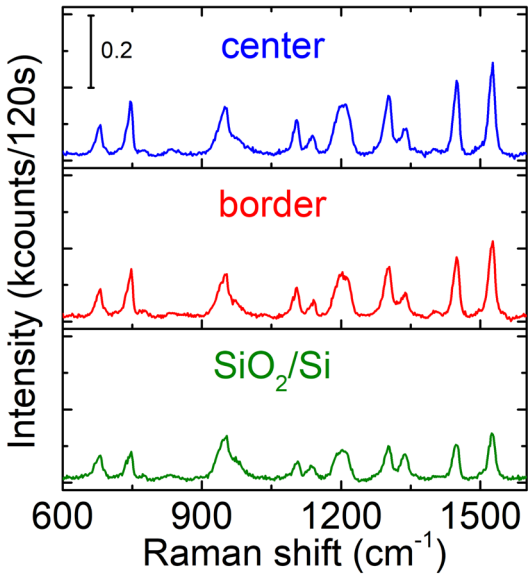

Figure S3: Raman spectra measured from CuPc/$MoSe_2$ using a radially polarized beam.

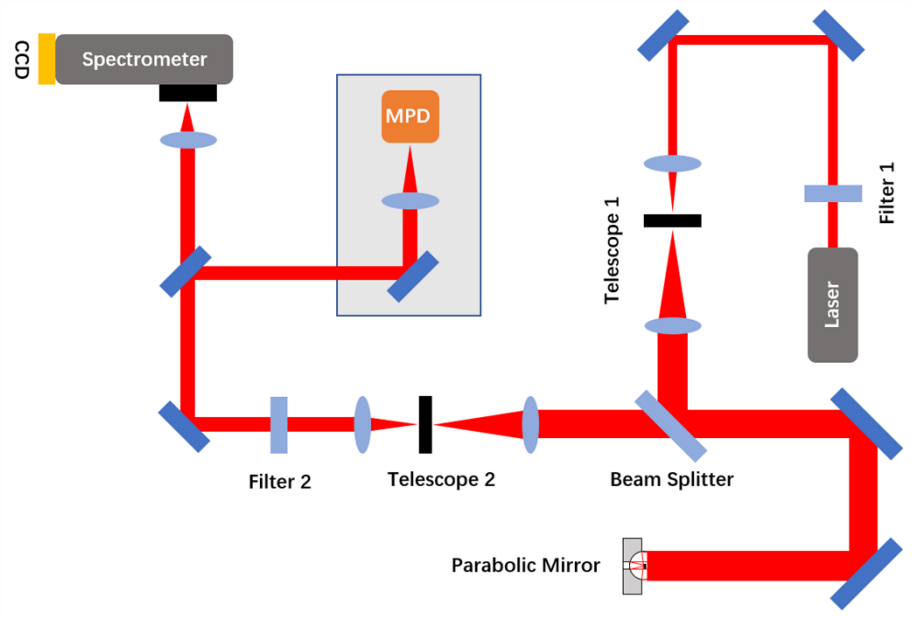

Figure S4: Schematic diagram of the custom-built confocal optical microscope with a parabolic mirror for light focusing and emission detection. Either a 636 nm (532 nm) CW laser or a 780 nm femtosecond pulsed laser are coupled to the microscope.